VDIC
NAND Flash Memory

VDNF64G08XS50XX8V25-Ⅱ
USER MANUAL

Version : A5

Contents

VDIC-NAND Flash Memory

HIGH-SPEED   3.3V   8G×8bit

1. DESCRIPTION

Offered in 8Gx8bit, the VDNF64G08XS50XX8V25-II is a 64G-bit NAND Flash Memory with spare capacity of 2048M-bits. The device operates at 3.3V. The I/O pins serve as the ports for address and data input/output as well as command input.

The VDNF64G08XS50XX8V25-II device is stacked with eight dies. The I/O ports and the control pins (ALE,CLE,#WE,#RE) of each die are connected.

A program operation can be performed in typical 200µs on the (2K+64)Byte page and an erase operation can be performed in typical 1.5ms on a (128K+4K)Byte block. Data in the data register can be read out at 25ns cycle time per Byte.

Every die has an on-chip write controller which is used to automate all program and erase functions including pulse repetition, where required, and internal verification and margining of data. Even the write-intensive systems can take advantage of the VDNF64G08XS50XX8V25-II's extended reliability of 100K program/erase cycles by providing ECC(Error Correcting Code) with real time mapping-out algorithm. Its NAND cell provides the most cost-effective solution for the solid state application market. The VDNF64G08XS50XX8V25-II is an optimum solution for large nonvolatile storage applications such as solid state data storage and advanced embedded control applications.

2. FEATURES

• Voltage Supply

- 3.3V device: 2.7 ~ 3.6 V

• Organization

- Memory Cell Array

-8dies x (1G + 32M)x 8 bit

- Data Register for each die

- (2K + 64) x 8bit

• Automatic Program and Erase

- Page Program for each die

-(2K + 64)Byte

- Block Erase for each die

- (128K + 4K)Byte

• Page Read Operation for each die

- Page Size

- (2K + 64)Byte

- Random Access : 25μs(Max.)

- Serial Page Access : 25ns(Min.)

• Fast Write Cycle Time

- Program time : 200μs(Typ.)

- Block Erase Time : 1.5ms(Typ.)

• Command/Address/Data Multiplexed I/O Port

• Hardware Data Protection

- Program/Erase Lockout During Power Transitions

• Reliable CMOS Floating-Gate Technology

- Endurance : 100K Program/Erase Cycles

- Data Retention : 10 Years

• Command Register Operation

• Intelligent Copy-Back with internal 1bit/528Byte EDC

• Package SOP-50

3. BLOCK DIAGRAM
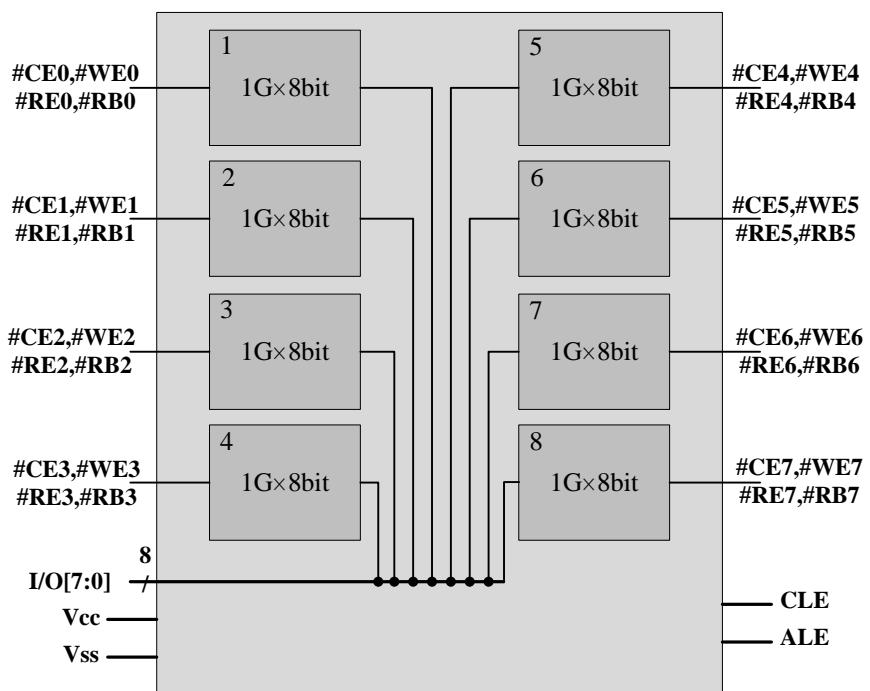
4. PIN DESCRIPTIONS– SOP-50

Pin Id	Pin #		Pin Id
#RB7	1	50	#RE7
#RB6	2	49	#RE6
#RB5	3	48	#RE5
#RB4	4	47	#RE4
#R/B3	5	46	#RE3
#R/B2	6	45	I/O7
#R/B1	7	44	I/O6
#R/B0	8	43	I/O5
#RE0	9	42	I/O4
#CE0	10	41	#RE2
#CE1	11	40	#RE1
#CE2	12	39	VCC
VCC	13	38	VCC
VSS	14	37	VSS
#CE3	15	36	VSS
#CE4	16	35	VSS
CLE	17	34	#CE5
ALE	18	33	I/O3
#WE0	19	32	I/O2
#WP	20	31	I/O1
#WE1	21	30	I/O0
#WE2	22	29	#CE7
#WE3	23	28	#CE6
#WE4	24	27	#WE7
#WE5	25	26	#WE6
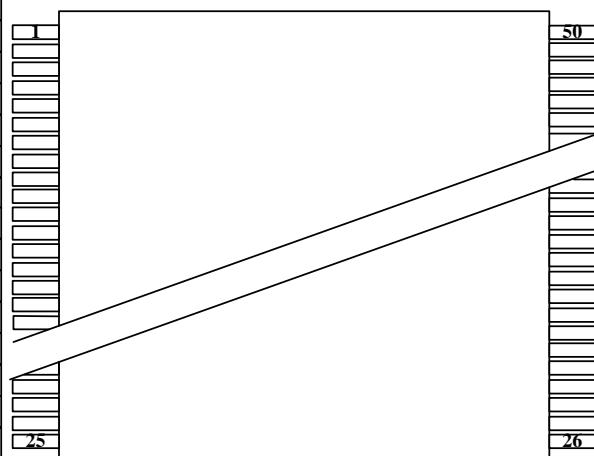
Name	Function
I/O0~I/O7	**DATA INPUTS/OUTPUTS** The I/O pins are used to input command, address and data, and to output data during read operations. The I/O pins float to high-z when the chip is deselected or when the outputs are disabled.
CLE	**COMMAND LATCH ENABLE** The CLE input controls the activating path for commands sent to the command register. When active high, commands are latched into the command register through the I/O ports on the rising edge of the #WE signal.
#CE0 (Die1) #CE1 (Die2) #CE2 (Die3) #CE3 (Die4) #CE4 (Die5) #CE5 (Die6) #CE6 (Die7) #CE7 (Die8)	**Die Enable Input .**When #CEn is Low, the command input cycle becomes valid. When #CEn is High, all inputs are ignored.
ALE	**ADDRESS LATCH ENABLE** The ALE input controls the activating path for the address to the internal address registers. Addresses are latched on the rising edge of #WE with ALE high.
#REn	**READ ENABLE** The #REn input is the serial data-out control, and when active , drives the data onto the I/O bus. Data is valid tREA after the falling edge of #RE which also increments the internal column address counter by one.
#WEn	**WRITE ENABLE** The #WEn input controls writes to the I/O port. Commands, address and data are latched on the rising edge of the #WE pulse.
#WP	**WRITE PROTECT** The #WP pin provides inadvertent write/erase protection during power transitions.The internal high voltage generator is reset when the #WP pin is active low.
#R/B0 (Die1)	**READY/BUSY OUTPUT**

Name	Function
#R/B1 (Die2)	The #R/Bn output indicates the status of the device operation. When low it indicates that a program, erase or random read operation is in process and returns to high state upon completion. It is an open drain output and does not float to high-z condition when the chip is deselected or when outputs are disabled.
#R/B2 (Die3)	
#R/B3 (Die4)	
#R/B4 (Die5)	
#R/B5 (Die6)	
#R/B6 (Die7)	
#R/B7 (Die8)	
VCC	**POWER** VCC is the power supply for device.
VSS	**GROUND**

5. ELECTRICAL SPECIFICATIONS

5.1. Absolute Maximum Ratings

Characteristics	Symbol	Maximum ratings	Unit
Voltage on V_{CC} supply relative to Vss	V_{CC}	-0.6 to +4.6	V
Voltage on any pin relative to Vss	V_{IN}	-0.6 to +4.6	V
Power Dissipation	P_D	1.5	W
Operating Temperature Range	T_{OPR}	-55~ +125	℃
Storage Temperature Range	T_{STG}	-65 to +150	℃

5.2. Recommended DC Operating Conditions

Parameter	Symbol	Min	Typ	Max	Unit
Supply voltage	V_{CC}	2.7	3.3	3.6	V
Input high voltage	V_{IH}	$V_{CC} \times 0.8$	——	$V_{CC}+0.3$	V

Parameter	Symbol	Min	Typ	Max	Unit
Input low voltage	V_{IL}	-0.3	——	$V_{CC}×0.2$	V

5.3. DC And Operating Characteristics

Parameter	Symbol	Test Conditions	Min	Max	Unit
Output voltage low level	V_{OL}	V_{CC}=3.6V I_{OL} =4mA	——	0.4	V
Output voltage high level	V_{OH}	V_{CC}=2.7V,I_{OH}= -2.1mA	2.4	——	V

6. Typical Application

7. ORDERING INFORMATION

1	2	3	4	5	6	7	8	9	10	11	12	13

VD . **NF** - **64G** - **08** . **X** . **S** . **50** - **X** . **X** - **8** . **V** - **25** **II**

VDIC

NAND FLASH

Capability：64G bit

Bus Width：8 bit

R= Radiation Data Tested;
V= Generic Radiation Data Available

Package: S=SOP

50=50 Pin

Temperature: E=0～70℃;I=-40～85℃;M=-55～125℃;S=Specific

Quality: E= Sample；B= Industry; M=Military; S= Space

Stacking Layer:8=8layer

Power Supply :V=3.3V

Speed:25= 25ns
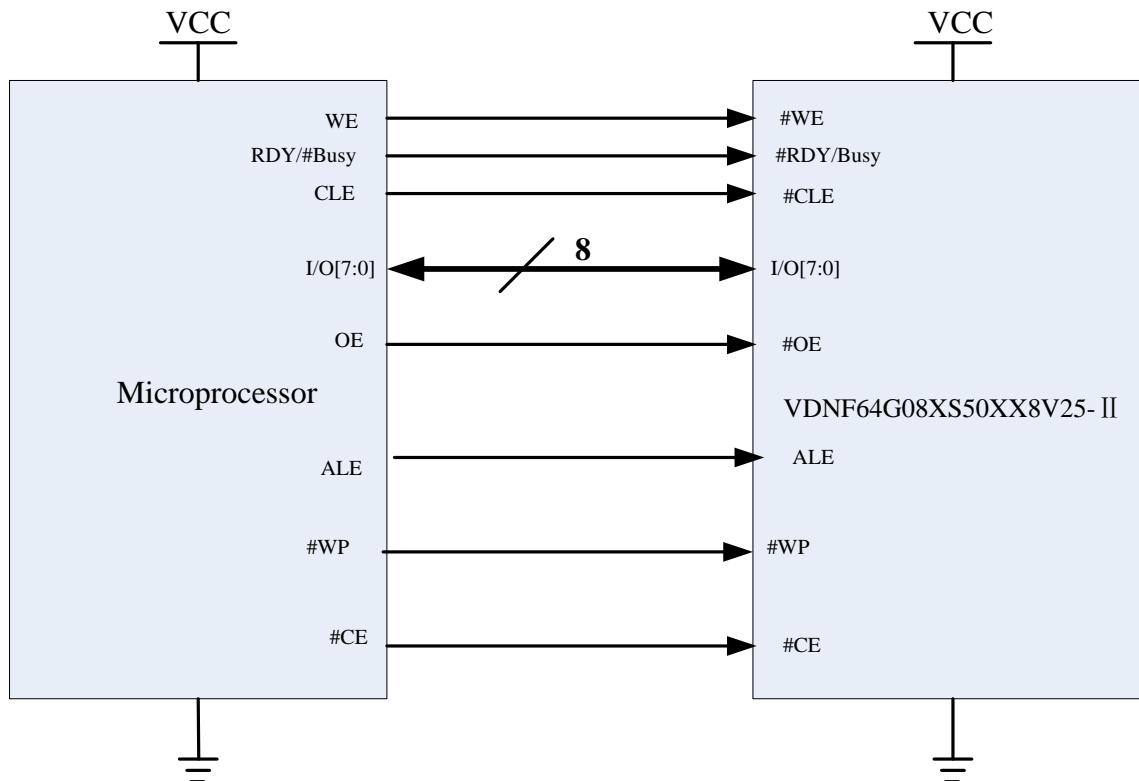
-Ⅱ**=Second Version**
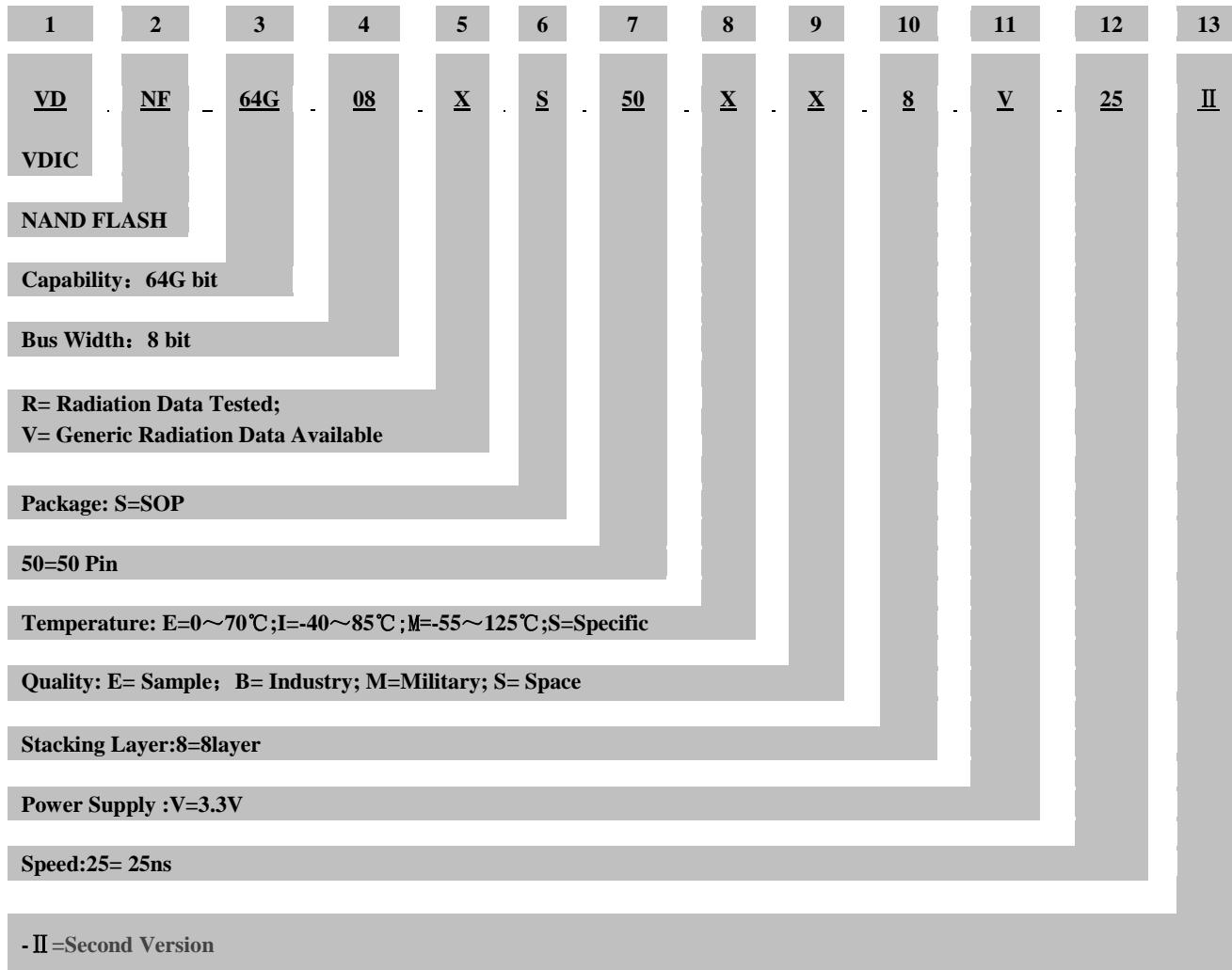
Part Number	Capacity (bit)	Bus Width (bit)	Radiation			Packaging	Temperature (℃)
			TID[1]	SEL[2]	SEU[3]		
VDNF64G08VS50EE8V25-II	64G	8	-	-	-	SOP50	0 ～ + 70
VDNF64G08VS50IB8V25-II	64G	8	-	-	-	SOP50	-40 ～ + 85
VDNF64G08VS50MB8V25-II	64G	8	-	-	-	SOP50	-55 ～ + 125
VDNF64G08VS50MM8V25-II	64G	8	-	-	-	SOP50	-55 ～ + 125
VDNF64G08RS50MS8V25-II	64G	8	>60	>62.5	1.3	SOP50	-55 ～ + 125

[1] TID: Total Dose （Krads(Si)）
[2] SEL: LET Threshold （Mev.cm2/mg）
[3] SEU:SEU Threshold （Mev.cm2/mg）

8. PACKAGE DIMENSIONS
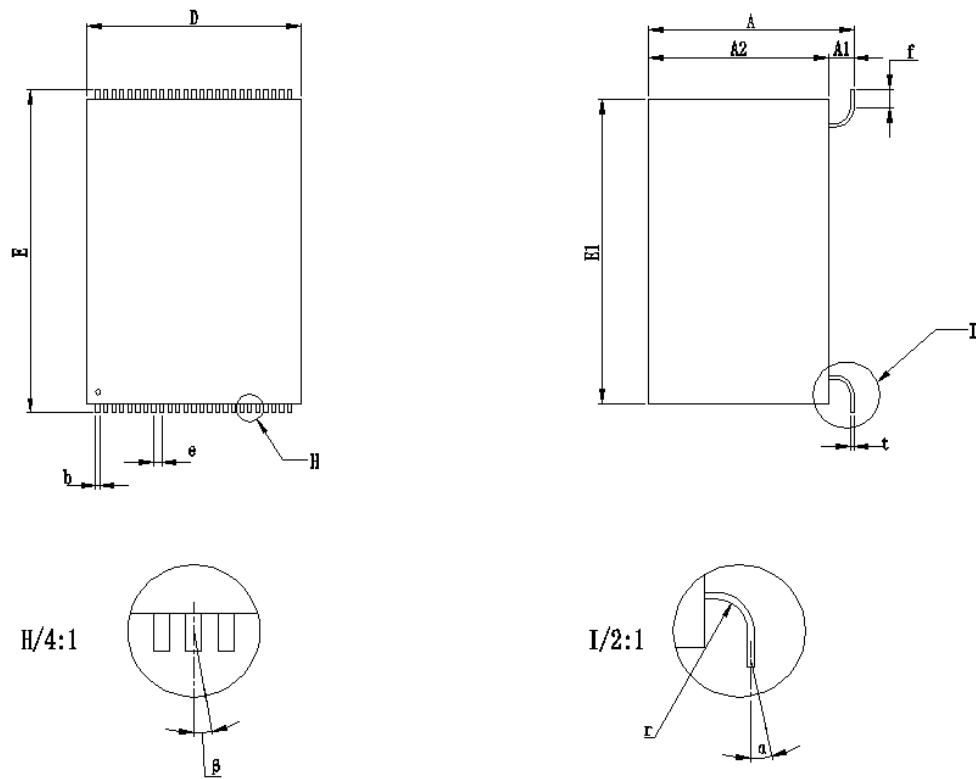
	Min	Max
A	12.30	12.80
A2	11.10	11.50
D	13.30	13.70
E	19.80	20.20
E1	18.80	19.20
f	1.20	
b	0.25	
e	0.50	
r	1.00	
t	0.20	
α	≤3°	
β	≤3°	
NOTE : 1. Unit : mm 2. A1= A - A2		

9. REVISION HISTORY

Revision	Date	Description of Change
A0	Nov 3,2015	First Created
A1	Mar 14,2016	Modified the PIN DESCRIPTIONS
A2	Aug 23,2016	Modified the ORDERING INFORMATION
A3	Jan 9,2017	Modified the PACKAGE DIMENSIONS
A4	Oct.25,2017	Changed company's name to Zhuhai Orbita Aerospace Science & Technology Co.，Ltd
A5	Mar 29,2018	Add or reduce chapters